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(54) **WIPE WITH EMBOSSED PATTERN**
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(52) **U.S. Cl.**
USPC **D5/26**

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D6/592, 595-598, 600, 602, 617; D32/40
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See application file for complete search history.

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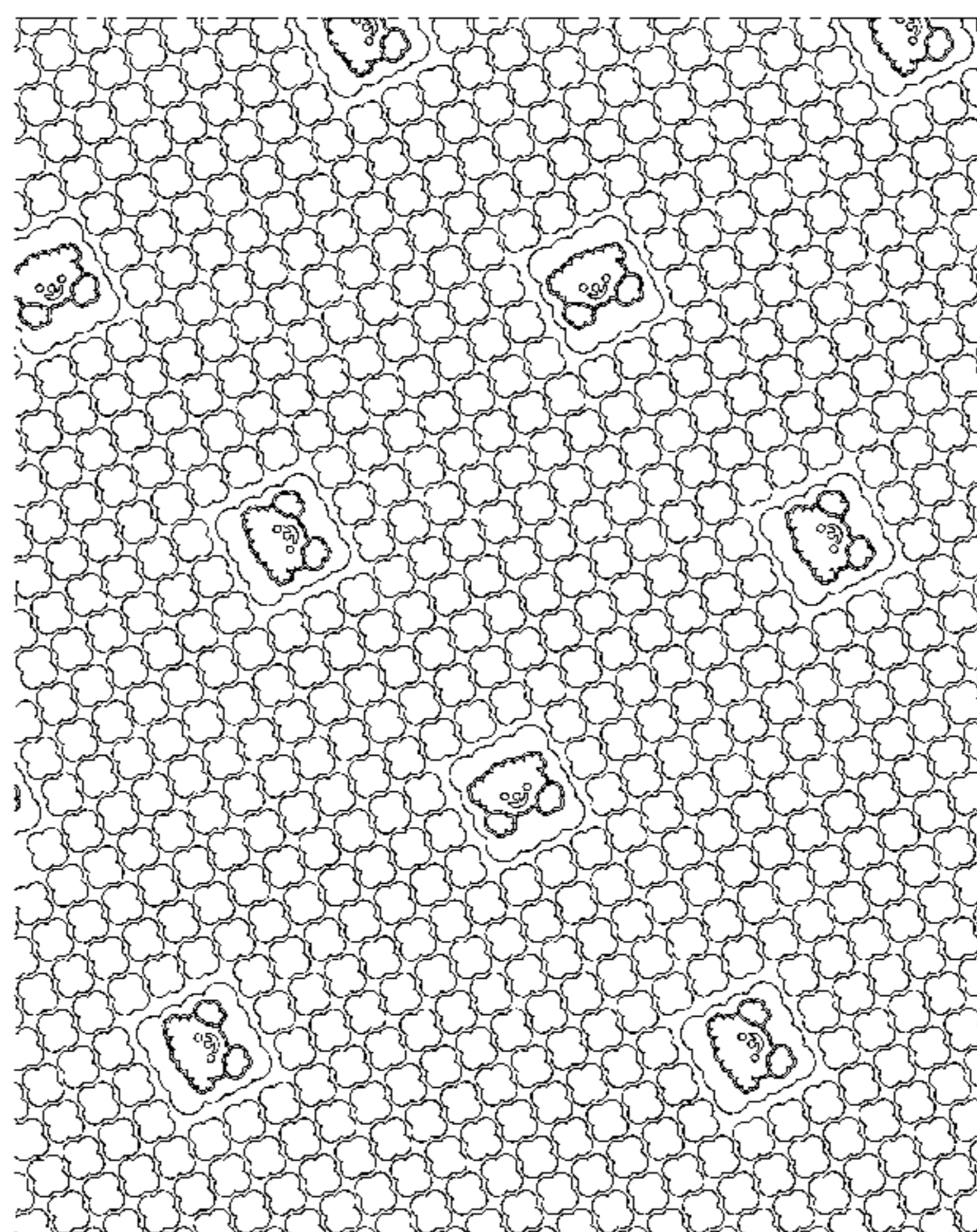
(57) **CLAIM**

The ornamental design for a wipe with embossing pattern, as shown and described.

DESCRIPTION

The sole FIGURE shows a top plan view of a wipe with embossing pattern. The broken lines surrounding the design depict the boundaries of the claim and form no part thereof. The thickness of the wipe with embossing pattern forms no part of the claim.

1 Claim, 1 Drawing Sheet



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